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FDS8960C

Dual N & P-Channel PowerTrench® MOSFET

General Description

These dual N- and P-Channel enhancement mode power field effect transistors are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state ressitance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Features

Q1: N-Channel

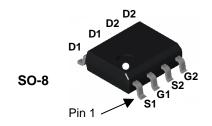
7.0A, 35V
$$\begin{aligned} R_{DS(on)} &= 0.024\Omega \ @ \ V_{GS} = 10V \\ R_{DS(on)} &= 0.032\Omega \ @ \ V_{GS} = 4.5V \end{aligned}$$

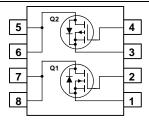
Q2: P-Channel

-5A, -35V
$$R_{DS(on)} = 0.053\Omega$$
 @ $V_{GS} = -10V$ $R_{DS(on)} = 0.087\Omega$ @ $V_{GS} = -4.5V$

- Fast switching speed
- RoHS compliant







Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V _{DSS}	Drain-Source Voltage		35	-35	V
V _{DS(Avalanche)}	Drain-Source Avalanche Voltage (maximu	40	-40	V	
V _{GSS}	Gate-Source Voltage		±20	±25	V
I_D	Drain Current - Continuous	(Note 1a)	7	-5	Α
	- Pulsed	-	20	-20	
P _D	Power Dissipation for Dual Operation		2	W	
	Power Dissipation for Single Operation (Note 1a)		1.		
		(Note 1b)	,		
		(Note 1c)	0	.9	
T _J , T _{STG}	Operating and Storage Junction Tempera	ture Range	-55 to +150		°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Marking and Ordering Information

		. •				
Device Marking		Device	Reel Size	Tape width	Quantity	
	FDS8960C	FDS8960C	13"	12mm	2500 units	

Symbol	Parameter	Test (Conditions	Type	Min	Тур	Max	Units
Drain-Se	ource Avalanche Rating	s						
E _{AS}	Drain-Source Avalanche	$V_{DD} = 35 \text{ V}, I_{D}$	= 7 A, L = 1 mH	Q1			24.5	mJ
	Energy (Single Pulse)	$V_{DD} = -35 \text{ V}, I_{D}$	=-5 A, L = 1 mH	Q2			12.5	mJ
AS	Drain-Source Avalanche Current			Q1 Q2		7 –5		А
Off Cha	racteristics							
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V,$ $V_{GS} = 0 V,$	$I_D = 250 \mu A$ $I_D = -250 \mu A$	Q1 Q2	35 -35			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A, Re$	eferenced to 25°C deferenced to 25°C	Q1 Q2		31 –40		mV/°C
DSS	Zero Gate Voltage Drain Current	$V_{DS} = 28 \text{ V},$ $V_{DS} = -28 \text{ V},$	$V_{GS} = 0 V$ $V_{GS} = 0 V$	Q1 Q2			1 –1	μА
GSSF	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V},$		Q1			100	nA
GSSR	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V},$					-100	nA
GSSR	Gate-Body Leakage, Forward	$V_{GS} = 25 \text{ V},$	$V_{DS} = 0 V$	Q2			100	nA
GSSF	Gate-Body Leakage, Reverse	$V_{GS} = -25 \text{ V},$	$V_{DS} = 0 V$				-100	nA
On Chai	racteristics (Note 2)							
$I_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS},$ $V_{DS} = V_{GS},$	$I_D = 250 \mu A$ $I_D = -250 \mu A$	Q1 Q2	1 –1	2 -1.8	3 -3	V
ΔV _{GS(th)} ΔT _J	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu\text{A}, \text{Re}$	ferenced to 25°C eferenced to 25°C	Q1 Q2		–5 4		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance		$I_D = 6 A$ = 7 A, $T_J = 125$ °C	Q1		20 25 29	24 32 37	mΩ
		$V_{GS} = -10 \text{ V},$ $V_{GS} = -4.5 \text{ V},$ $V_{GS} = -10 \text{ V}, \text{ I}_{D}$	$I_D = -5 \text{ A}$ $I_D = -4 \text{ A}$ $I_D = -4 \text{ A}$ $I_D = -5 \text{ A}$	Q2		44 70 61	53 87 79	
] FS	Forward Transconductance	$V_{DS} = 5 \text{ V},$ $V_{DS} = -5 \text{ V},$	_	Q1 Q2		23 9		S
Dynami	c Characteristics							
C _{iss}	Input Capacitance	Q1 V _{DS} = 15 V, V _{GS}	= 0 V, f = 1.0 MHz	Q1 Q2		570 540		pF
C _{oss}	Output Capacitance	Q2		Q1 Q2		126 113		pF
C _{rss}	Reverse Transfer Capacitance	$V_{DS} = -15 \text{ V}, \text{ V}_{G}$	s = 0 V, f = 1.0 MHz	Q1 Q2 Q1		52 60 2		pF
R_{G}		f = 1.0 MHz						

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Switchin	g Characteristics (Note 2	2)					
$t_{d(on)}$	Turn-On Delay Time	Q1 V _{DD} = 15 V, I _D = 1 A,	Q1 Q2		8 12	16 22	ns
t _r	Turn-On Rise Time	$V_{GS} = 10V$, $R_{GEN} = 6 \Omega$	Q1 Q2		5 16	10 29	ns
t _{d(off)}	Turn-Off Delay Time	Q2 $V_{DD} = -15 \text{ V}, I_{D} = -1 \text{ A},$	Q1 Q2		23 20	37 32	ns
t _f	Turn-Off Fall Time	$V_{GS} = -10V$, $R_{GEN} = 6 \Omega$	Q1 Q2		3 5	6 10	ns
Q_g	Total Gate Charge	Q1 V _{DS} = 15 V, I _D = 7 A, V _{GS} = 5 V	Q1 Q2		5.5 5.7	7.7 8	nC
Q _{gs}	Gate-Source Charge	Q2	Q1 Q2		1.8 1.8		nC
Q_{gd}	Gate-Drain Charge	$V_{DS} = -15 \text{ V}, I_{D} = -5 \text{ A}, V_{GS} = -5 \text{ V}$	Q1 Q2		1.8 2		nC
Drain-S	ource Diode Characteri	stics					
Is	Maximum Continuous Drain-S	Source Diode Forward Current	Q1 Q2			1.3 -1.3	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 1.3 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V}, I_S = -1.3 \text{ A}$ (Note 2)	Q1 Q2		0.8 -0.8	1.2 -1.2	V
t _{rr}	Diode Reverse Recovery Time	Q1 $I_F = 7 \text{ A, } d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$	Q1 Q2		20 17		nS
Q _{rr}	Diode Reverse Recovery Charge	Q2 $I_F = -5 \text{ A}, d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$	Q1 Q2		10 5		nC

Notes:

1. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a) 78°C/W when mounted on a 0.5 in² pad of 2 oz copper



b) 125°C/W when mounted on a .02 in² pad of 2 oz copper



c) 135°C/W when mounted on a minimum pad.

- Scale 1 : 1 on letter size paper
- 2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%
- 3. BV(avalanche) Single-Pulse rating is guaranteed by design if device is operated within the UIS SOA boundary of the device.

Typical Characteristics: Q1 (N-Channel)

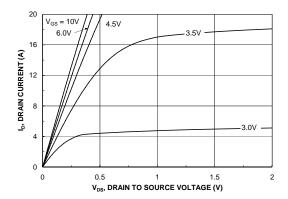


Figure 1. On-Region Characteristics.

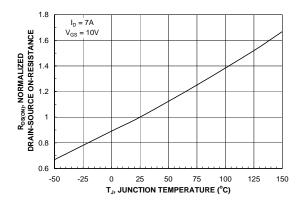


Figure 3. On-Resistance Variation with Temperature.

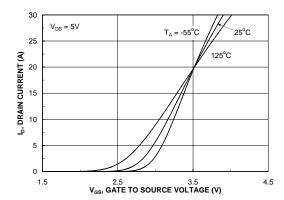


Figure 5. Transfer Characteristics.

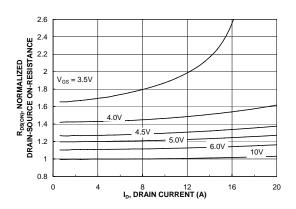


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

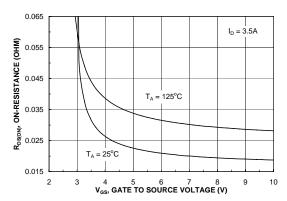


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

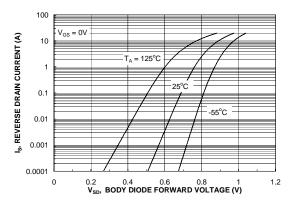


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics: Q1 (N-Channel)

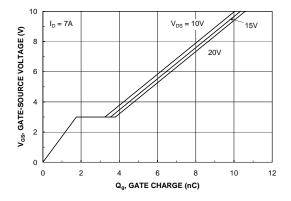


Figure 7. Gate Charge Characteristics.

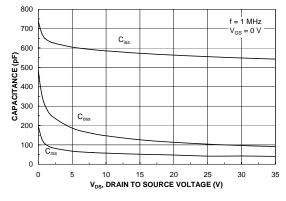


Figure 8. Capacitance Characteristics.

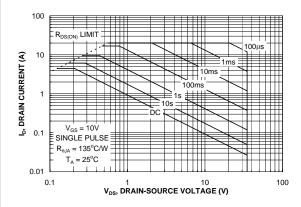


Figure 9. Maximum Safe Operating Area.

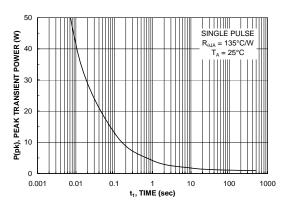


Figure 10. Single Pulse Maximum Power Dissipation.

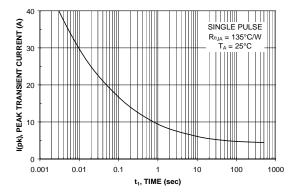


Figure 11. Single Pulse Maximum Peak Current

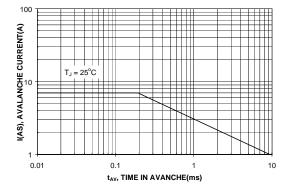


Figure 12. Unclamped Inductive Switching Capability

Typical Characteristics: Q2 (P-Channel)

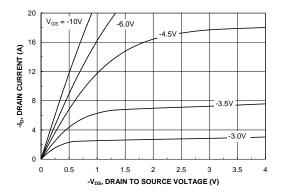


Figure 13. On-Region Characteristics.

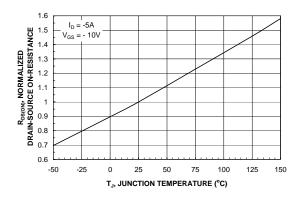


Figure 15. On-Resistance Variation with Temperature.

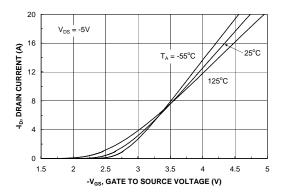


Figure 17. Transfer Characteristics.

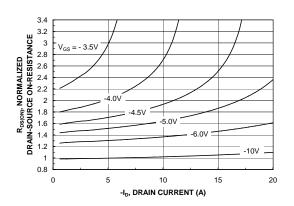


Figure 14. On-Resistance Variation with Drain Current and Gate Voltage.

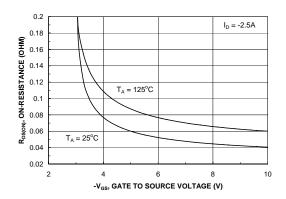


Figure 16. On-Resistance Variation with Gate-to-Source Voltage.

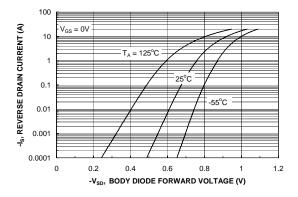


Figure 18. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics: Q2 (P-Channel)

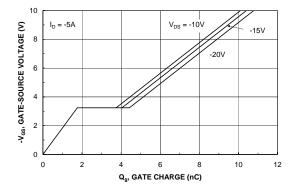


Figure 19. Gate Charge Characteristics.

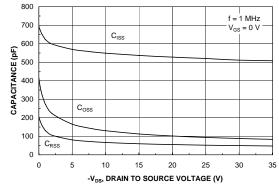


Figure 20. Capacitance Characteristics.

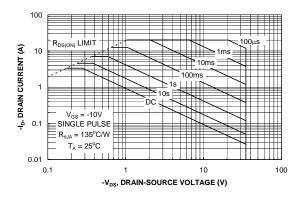


Figure 21. Maximum Safe Operating Area.

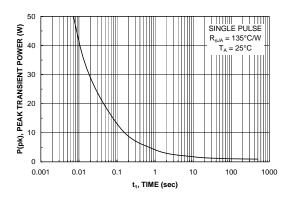


Figure 22. Single Pulse Maximum Power Dissipation.

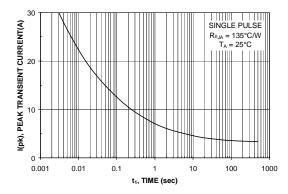


Figure 23. Single Pulse Maximum Peak Current

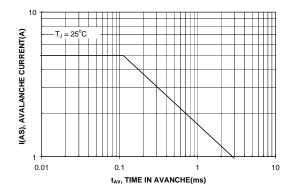


Figure 24. Unclamped Inductive Switching Capability

Typical Characteristics

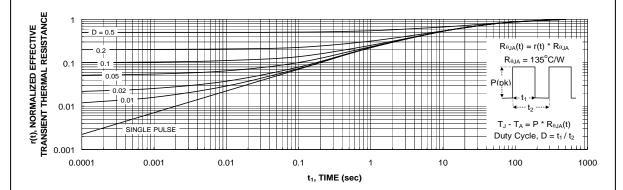


Figure 25. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c.

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